

Notice of References Cited

Application/Control No.

10/697,899

Applicant(s)/Patent Under
Reexamination
BEST ET AL.

Examiner

Binh V. Ho

Art Unit

2163

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0254907 A1	12-2004	Crow et al.	707/001
*	B	US-2004/0139273 A1	07-2004	Doucette et al.	711/100
*	C	US-2003/0182317 A1	09-2003	Kahn et al.	707/200
*	D	US-2004/0123039 A1	06-2004	Berks et al.	711/133
*	E	US-2005/0234867 A1	10-2005	Shinkai, Yoshitake	707/001
*	F	US-2003/0191745 A1	10-2003	Jiang et al.	707/2
*	G	US-5,963,962 A	10-1999	Hitz et al.	707/202
*	H	US-5,828,876 A	10-1998	Fish et al.	707/1
*	I	US-6,571,261 B1	05-2003	Wang-Knop et al.	707/206
*	J	US-2005/0050110 A1	03-2005	Sawdon et al.	707/201
*	K	US-7,010,554 B2	03-2006	Jiang et al.	707/205
*	L	US-6,615,224 B1	09-2003	Davis, Lewis B.	707/202
*	M	US-2005/0050110	03-2005	Sawdon et al.	707/201

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.